Abstracts

Trends in Mixer Damage

C.M. Glenn and R.V. Garver. "Trends in Mixer Damage." 1989 MTT-S International Microwave Symposium Digest 89.1 (1989 Vol. I [MWSYM]): 475-477.

The dynamic damage properties of 74 pairs of 1N23 X-band mixer diodes have been measured using a train of 30 short pulses at a 1-pps repetition rate. A first 30-uJ pulse caused a 3-dB degradation of conversion loss. The damage of successive 16-uJ pulses asymptotically approached 3-dB.

❑ Return to main document.

Click on title for a complete paper.